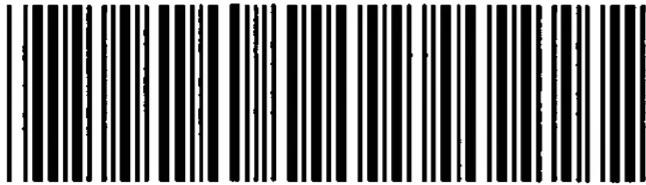


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|--|--------------------------------|--|--|--|
| Search Notes  | Application/Control No. | | Applicant(s)/Patent under Reexamination | |
| | 10/649,198 | | KOUGIOURIS ET AL. | |
| | Examiner | | Art Unit | |
| | Maikhanh Nguyen | | 2176 | |

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| Class | Subclass | Date | Examiner |
| 715 | 513 | 8/20/2005 | MK |
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| Updated | Search | 4/27/2006 | MK |
| Updated | Search | 2/10/2007 | MK |
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| INTERFERENCE SEARCHED | | | |
|-----------------------|----------|------|----------|
| Class | Subclass | Date | Examiner |
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| SEARCH NOTES (INCLUDING SEARCH STRATEGY) | | |
|--|-----------|------|
| | DATE | EXMR |
| Inventor Name Search | 8/20/2005 | MK |
| West Search (See search history printout) | 8/20/2005 | MK |
| NPL (IEEE) | 8/20/2005 | MK |
| NPL (IEEE) | 4/27/2006 | MK |
| West Updated (USPAT, PG-PUB, EPO, JPO, DERWENT, IBM_TDB) | 4/27/2006 | MK |
| West Updated (USPAT, PG-PUB, EPO, JPO, DERWENT, IBM_TDB) | 2/10/2007 | MK |
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